


<b>Search Notes</b>  	<b>Application/Control No.</b>  10550065	<b>Applicant(s)/Patent Under Reexamination</b>  TACHIBANA ET AL.
	<b>Examiner</b>  Deuble, Mark A	<b>Art Unit</b>  3651

SEARCHED			
Class	Subclass	Date	Examiner
198	791		
	790	12/20/06	md

SEARCH NOTES		
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INTERFERENCE SEARCH			
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